

# 偏光膜、光學材料量測系統

## Absolute Reflectance Measurement System

### V-7000 + ARM



- 高精度 UV / VIS (NIR) 光譜儀
- 測量範圍：± 8 Abs
- 波長解析度：0.049 nm
- 迷光率：≤ 0.00007% (220 nm)
- 波長範圍：V-7100 : 175-900 nm  
V-7200 : 175-3300 nm  
V-7400 : 175-1800 nm

#### 應用領域：

- 影音設備 – Dichroic prism or mirror examination for CD / DVD compatible player.
- 光電元件 – Evaluation of spectral properties of Optical elements
- F P D – Evaluation of spectral properties and color according to view angle.
- 半導體 – Measurement of film thickness on a wafer.
- 太陽能 – Silicon layer properties.
- 塗料 – Colorimetry for metallic colors etc.
- 化粧品 – Evaluation of color according to angle of cosmetics.



### Absolute Reflection Measurement

#### 絕對反射測量裝置

- 專為測量光學元件設計之附件
- 可進行不同角度之反射式或穿透式測量
- 測角度：5° to 60° (反射式)  
0° to 60° (穿透式)

- 量測波長：
  - ARM-500V250 to 850 (for V-650 / 660)
  - ARM-500N250 to 2000 (for V-670)
  - VAR-7010250 to 850 (for V-7100)
  - VAR-7020250 to 2000 (for V-7200)
  - VAR-7020250 to 1800 (for V-7300)

